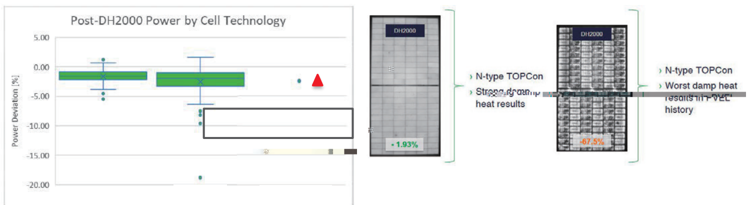
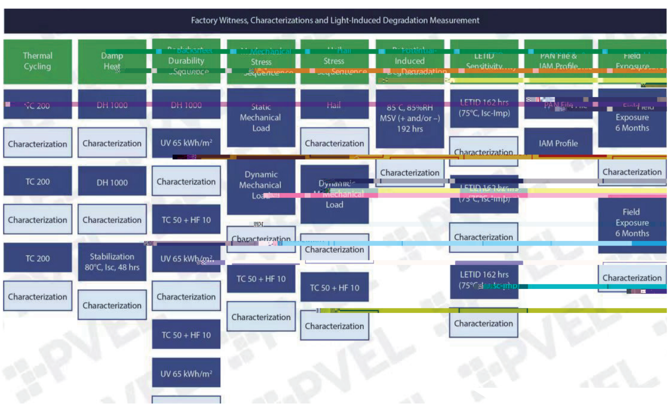
*Note-as per PVEL PQP: BOM Test Requirements,this test is not required for this BOM.Contact PVEL for more information on the representative results from other BOMs from the same manufacturer.



*Source:NREL,Degradation Mechanisms in TOPCon/POLO Solar Cells



Factory Witness, Characterizations and Light-Induced Degradation Measurement
Thermal Cycling
Damp Heat
Durability
Stress
Stress
Induced
Exposure
TC 200
DH 1000
DH 1000
Static Mechanical Load
Hail
85°C, 85%RH MSV (+ and/or –) 192 hrs
LETID 162 hrs (75°C, Isc-Imp)
Exposure 6 Months
Characterization
UV 65 kWh/m²
IAM Profile
Dynamic Mechanical Load
TC 50 + HF 10
Field Exposure 6 Months
Stabilization 80°C, Isc, 48 hrs

module reliability test as part
m (PQP), the JinkoSolar's
JKM555N-72HL4-BDV) have
anding in every category.
+LETID" under DH2000/BO,
Performer" in module reliabili-

s DH2000 test on hundred of
erage degradation was
ogies (PERC, TOPCon, HJT,
ar's N-type TOPCon bifacial
as 0.55%, the lowest among

ates long-term degradation
l in high temperatures and
isture and heat can weaken
le together. When the adhe-
ns due to low-quality compo-
ion processes, moisture can
ternal materials. The result is
fety issues.

ting modules to a constant
an environmental chamber
est is -two times the duration
der to identify additional
ombination of high heat and
dule layers.

es can lead to a destabiliza-
complexes. This leads to
ells, but is less of a concern
s N-type TOPCon

JinkoSolar N-type TOPCon Module Outperforms in PVEL Test in Every Category About PVEL